



#6

SHEET 1 OF 2

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

216780US-2 DIV

SERIAL NO.

10/028,766

LIST OF REFERENCES CITED BY APPLICANT
(Use Several Sheets if Necessary)APPLICANT
Satoshi SHIMIZU, et al.

FILING DATE

12-28-01

GROUP

2811

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Cn</i>	AA	5,021,353	6-4-91	LOWREY, et al.			
<i>Cn</i>	AB	5,102,816	4-7-92	MANUKONDA, et al.			
<i>Cn</i>	AC	5,491,099	2-13-96	HSU			
<i>Cn</i>	AD	5,518,960	5-21-96	TSUCHIMOTO			
<i>Cn</i>	AE	5,554,871	9-10-96	YAMASHITA, et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
<i>Cn</i>	AL	7-106280	4-21-95	JAPAN		X
<i>Cn</i>	AM	6-13402	1-21-94	JAPAN		X
<i>Cn</i>	AN	63-318779	12-27-88	JAPAN		X
<i>Cn</i>	AO	6-326122	11-25-94	JAPAN		X
<i>Cn</i>	AP	5-47785	2-26-93	JAPAN		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Cn</i>	AR	M. SEKINE, et al., "Self-Aligned Tungsten Strapped Source/Drain and Gate Technology Realizing the Lowest Sheet Resistance for Sub-quarter Micron CMOS", IEDM, 1994, pages 493-496
	AS	
	AT	

EXAMINER

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12-9-02

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SHEET 2 OF 2Form PTO 1449
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	BA						
	BB						
	BC						
	BD						
	BE						
	BF						
	BG						
	BH						
	BI						
	BJ						
	BK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
<i>on</i>	BL	3-288443	12-18-91	JAPAN		X
<i>on</i>	BM	9-8292	1-10-97	JAPAN		X
<i>on</i>	BN	8-255766	10-1-96	JAPAN	X	
	BO					
	BP					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	BR	
	BS	
	BT	

EXAMINER

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